UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/611,307	07/01/2003	Akihiro Matsuda	10873.352USRE	10873.352USRE 3972	
53148 HAMRE, SCH	7590 08/01/2007 UMANN, MUELLER & I	EXAMINER .			
P.O. BOX 2902-0902 MINNEAPOLIS, MN 55402			DICKEY, THOMAS L		
			ART UNIT	PAPER NUMBER	
			2826		
			MAIL DATE	DELIVERY MODE	
	•		08/01/2007	PAPER	

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Advisory Action Before the Filing of an Appeal Brief

Application No.	Applicant(s)	Applicant(s)		
10/611,307	MATSUDA ET AL.			
Examiner	Art Unit			
Thomas L. Dickey	2826			

	Thomas L. Dickey	2826	
The MAILING DATE of this communication appe	ears on the cover sheet with the o	correspondence add	ress
THE REPLY FILED <u>20 July 2007</u> FAILS TO PLACE THIS APP	LICATION IN CONDITION FOR AL	LOWANCE.	
The reply was filed after a final rejection, but prior to or or this application, applicant must timely file one of the follow places the application in condition for allowance; (2) a No a Request for Continued Examination (RCE) in compliant time periods:	n the same day as filing a Notice of wing replies: (1) an amendment, aff otice of Appeal (with appeal fee) in a	Appeal. To avoid aba idavit, or other evider compliance with 37 C	nce, which FR 41.31; or (3)
a) The period for reply expires 3 months from the mailing date	e of the final rejection.		
b) The period for reply expires on: (1) the mailing date of this A no event, however, will the statutory period for reply expire I	Advisory Action, or (2) the date set forth ater than SIX MONTHS from the mailin	in the final rejection, wh g date of the final rejecti	ichever is later. In
Examiner Note: If box 1 is checked, check either box (a) or TWO MONTHS OF THE FINAL REJECTION. See MPEP 7	06.07(f).		
Extensions of time may be obtained under 37 CFR 1.136(a). The date have been filed is the date for purposes of determining the period of exunder 37 CFR 1.17(a) is calculated from: (1) the expiration date of the set forth in (b) above, if checked. Any reply received by the Office laternay reduce any earned patent term adjustment. See 37 CFR 1.704(b) NOTICE OF APPEAL	tension and the corresponding amount shortened statutory period for reply orig r than three months after the mailing da	of the fee. The approprinally set in the final Offi	iate extension fee ce action: or (2) as
2. The Notice of Appeal was filed on A brief in comp	pliance with 37 CFR 41 37 must be	filed within two month	ns of the date of
filing the Notice of Appeal (37 CFR 41.37(a)), or any exte a Notice of Appeal has been filed, any reply must be filed AMENDMENTS	nsion thereof (37 CFR 41.37(e)), to	avoid dismissal of th	e appeal. Since
3. ☑ The proposed amendment(s) filed after a final rejection,	but prior to the date of filing a brief	will not be entered b	acausa acausa
(a) They raise new issues that would require further co	insideration and/or search (see NO	TE below):	ecause
(b) They raise the issue of new matter (see NOTE below		,,	
(c) They are not deemed to place the application in be appeal; and/or	tter form for appeal by materially re	ducing or simplifying	the issues for
(d) They present additional claims without canceling a	corresponding number of finally rej	ected claims.	
NOTE: See Continuation Sheet. (See 37 CFR 1.1	16 and 41.33(a)).		
$oxed{4}$. \square The amendments are not in compliance with 37 CFR 1.1	21. See attached Notice of Non-Co	mpliant Amendment	(PTOL-324).
5. Applicant's reply has overcome the following rejection(s)	· •		
 Newly proposed or amended claim(s) would be a non-allowable claim(s). 			-
7. For purposes of appeal, the proposed amendment(s): a) how the new or amended claims would be rejected is pro The status of the claim(s) is (or will be) as follows: Claim(s) allowed:		ll be entered and an e	explanation of
Claim(s) objected to:			
Claim(s) rejected: <u>1-5 and 15-18</u> .	·		
Claim(s) withdrawn from consideration: AFFIDAVIT OR OTHER EVIDENCE			
B. The affidavit or other evidence filed after a final action, but	it before or on the date of filing a N	otice of Appeal will no	ot be entered
because applicant failed to provide a showing of good an was not earlier presented. See 37 CFR 1.116(e).	d sufficient reasons why the affiday	vit or other evidence is	necessary and
 The affidavit or other evidence filed after the date of filing entered because the affidavit or other evidence failed to of showing a good and sufficient reasons why it is necessar 	overcome <u>all</u> rejections under appe y and was not earlier presented. S	al and/or appellant fa ee 37 CFR 41.33(d)(ils to provide a 1).
10. The affidavit or other evidence is entered. An explanation REQUEST FOR RECONSIDERATION/OTHER	n of the status of the claims after e	ntry is below or attacl	ned.
1. The request for reconsideration has been considered but	it does NOT place the application in	n condition for allowa	nce because:
2. Note the attached Information Disclosure Statement(s).	(PTO/SB/08 or PTO-1449) Paper N	lo(s)	
3. Other:		Thomas I Dickey	Doy,
•		Dalas and Every	(/

Primary Examiner Art Unit: 2826

Continuation of 3. NOTE: Proposed Claim 15 is broader than claim 15 as previously searched. As previously searched, claim 15 required "a dummy area on the substrate." This limitation is removed from proposed claim 15. Whether the prior art discloses or suggests a semiconductor area surrounded by a plurality of semiconductor elements not necessarily to be found in a semiconductor area creates a new issue not previously searched or considered.

Also, proposed Claim 15 recites a plurality of semiconductor elements EACH comprising a top electrode and a bottom electrode. This amounts to a recital of a plurality of electrodes, actually two (top and bottom) such pluralities. Likewise, proposed Claim 15 recites a plurality of dummy semiconductor elements EACH comprising a top electrode and a bottom electrode. This amounts to a recital of a plurality of dummy electrodes, actually (again) two such pluralities. It seems to the examiner that the proposed recital of these pluralities of electrodes and dummy electrodes creates a new, §112 issue. On the face of things it appears indefinite which of said plurality of electrodes is referred to by the recital of "the electrode" in line 21. Again, on the face of things it appears indefinite which of said plurality of dummy electrodes is referred to by the recital of "the dummy electrode" in line 21.

The Examiner wishes at this time to point out to Applicant two recent cases, Ex parte CAROLYN RAMSEY CATAN, Appeal 2007-0820, Application 09/734,808 (BPAI, 7/3/07, PRECEDENTIAL) (http://www.uspto.gov/web/offices/dcom/bpai/prec/fd070820.pdf) and LEAPFROG ENT. INC. v. FISHER-PRICE, INC., 485 F.3d 1157, 1161, 82 USPQ2d 1687, 1690-91 (Fed. Cir. 2007). CATAN quotes LEAPFROG for the proposition that "The combination of familiar elements according to known methods is likely to be obvious when it does no more than yield predictable results." CATAN, Slip Op. at 12.

The CATAN panel goes on to say that:

As in LEAPFROG, the device defined by claim 5 is an adaptation of an old invention (Nakano) using newer technology that is commonly available and understood in the art (Harada). Adding bioauthentication to the Nakano device does no more to Nakano's device than it would do if it were added any other device. The function remains the same. Predictably, bioauthentication adds greater security and reliability to an authorization process (FF 12). This variation on Nakano's device, whereby the manual authentication means of the Nakano device is replaced with Harada's bioauthentication means, appears to present no unexpected technological advance in the art. One of ordinary skill in the art of consumer electronic devices would have found it obvious to update the Nakano device with the modern authentication components of the Harada bioauthentication means and thereby gaining, predictably, the commonly understood benefits of such adaptation, that is, a secure and reliable authentication procedure (FF 12).

CATAN, Slip Op. at 18. The Examiner is aware of references demonstrating that when the DRAM industry went to COB (capacitor-overbitline) configurations, it became commonplace to add "dummy" capacitors on chips, between areas dedicated to DRAM memory. Without these "dummy" capacitors these areas were subject to "dishing" when CMP (chemical-mechanical-polishing) was performed. These "dummy" capacitors were spaced exactly as the real ones were, because spacing between capacitors determined the structures' ability to stand up to the pressure of CMP, just as spacing between steel columns of the first floor of a building determines its ability to stand up to the pressure of floors. These references should already be of record. Likewise, the record should already contain references establishing that high-k or ferroelectric memory capacitors were, at time of Applicants' invention, "newer technology that is commonly available and understood in the art" (borrowing a phrase from the CATAN panel).

In the Examiner's opinion, Applicants' claims will not pass obviousness muster under the CATAN or LEAPFROG standards, if they read on a device that could simply have been produced by combining the known elements of "anti-dishing" dummy capacitors and high-capacity (or non-volatile) high-k or ferroelectric memory capacitors.